

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments
1	BRS	L1	1	20040065844.pn.	USPA T; US-P GPUB	2004/04/29 16:19	
2	BRS	L2	67	(electron adj source) with emitter with beam	USPA T; US-P GPUB	2004/04/29 16:27	
3	BRS	L3	2	L2 and (first near2 deflect\$5 near3 stage)	USPA T; US-P GPUB	2004/04/29 16:35	
4	BRS	L5	877	(high adj energy adj electron adj diffraction) or (RHEED)	USPA T; US-P GPUB	2004/04/29 16:27	
5	BRS	L6	1	L5 and ((electron adj source) with emitter with beam\$2)	USPA T; US-P GPUB	2004/04/29 16:30	
6	BRS	L7	4	L5 and ((electron adj source) with (sample or specimen or target))	USPA T; US-P GPUB	2004/04/29 16:34	
7	BRS	L8	3	L7 not L1	USPA T; US-P GPUB	2004/04/29 16:34	
8	BRS	L10	4	L9 and (electron near3 (source or emitter or generator))	USPA T; US-P GPUB	2004/04/29 16:39	
9	BRS	L11	2	L10 and (first near4 deflect\$5)	USPA T; US-P GPUB	2004/04/29 16:39	
10	BRS	L12	1	L11 and (second near4 deflect\$5)	USPA T; US-P GPUB	2004/04/29 16:40	
11	BRS	L9	4	L8 or L4	USPA T; US-P GPUB	2004/04/29 16:39	
12	BRS	L4	1	L2 and (RHEED)	USPA T; US-P GPUB	2004/04/29 16:38	
13	BRS	L13	1	L3 not L1	USPA T; US-P GPUB	2004/04/29 16:38	

	Error Definition	Er ro rs
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4		0
5		0
6		0
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9		0
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13		0

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments
14	BRS	L14	4	L8 or L13	USPA T; US-P GPUB	2004/04/2 9 16:39	
15	BRS	L17	1	L16 and (second near4 deflect\$5)	USPA T; US-P GPUB	2004/04/2 9 16:58	
16	BRS	L18	1	L16 and ((second near4 deflect\$5) with (sample or target or specimen))	USPA T; US-P GPUB	2004/04/2 9 16:49	
17	BRS	L16	2	L15 and (first near4 deflect\$5)	USPA T; US-P GPUB	2004/04/2 9 16:46	
18	BRS	L19	0	L18 and (magnet\$4 near4 shield\$5)	USPA T; US-P GPUB	2004/04/2 9 16:47	
19	BRS	L20	0	L18 and (magnet\$4 with shield\$5)	USPA T; US-P GPUB	2004/04/2 9 16:47	
20	BRS	L15	4	L14 and (electron near3 (source or emitter or generator))	USPA T; US-P GPUB	2004/04/2 9 16:47	
21	BRS	L21	0	L15 and (magnet\$4 with shield\$5)	USPA T; US-P GPUB	2004/04/2 9 16:48	
22	BRS	L22	18	L5 and (magnet\$4 with shield\$5)	USPA T; US-P GPUB	2004/04/2 9 17:12	
23	BRS	L23	1	L22 and ((second near4 deflect\$5) with (sample or target or specimen))	USPA T; US-P GPUB	2004/04/2 9 16:49	
24	BRS	L25	0	L24 and (casing with aperture with (point or slit))	USPA T; US-P GPUB	2004/04/2 9 17:11	
25	BRS	L24	2	L22 and (aperture with (point\$3 or slit))	USPA T; US-P GPUB	2004/04/2 9 16:54	
26	BRS	L26	1	L22 and ((second near4 deflect\$5) with beam with correct\$5)	USPA T; US-P GPUB	2004/04/2 9 16:56	

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	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments
27	BRS	L27	17	L22 not L1	USPA T; US-P GPUB	2004/04/29 16:56	
28	BRS	L28	0	L27 and (aperture with foil)	USPA T; US-P GPUB	2004/04/29 16:57	
29	BRS	L29	0	(L5 not L1) and (aperture with foil)	USPA T; US-P GPUB	2004/04/29 16:58	
30	BRS	L30	876	L5 not L1	USPA T; US-P GPUB	2004/04/29 16:58	
31	BRS	L31	4	L30 and (second near4 deflect\$5)	USPA T; US-P GPUB	2004/04/29 17:13	
32	BRS	L32	1	L22 and (casing with aperture)	USPA T; US-P GPUB	2004/04/29 17:11	
33	BRS	L33	17	L27 and (magnet\$4 with shield\$5)	USPA T; US-P GPUB	2004/04/29 17:12	
34	BRS	L34	0	L33 and (second near4 deflect\$5)	USPA T; US-P GPUB	2004/04/29 17:13	

	Error Definition	Er ro rs
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29		0
30		0
31		0
32		0
33		0
34		0

L Number	Hits	Search Text	DB	Time stamp
1	1	20040065844.pn.	USPAT;	2004/04/29
2	67	((electron adj source) with emitter with beam	US-PGPUB	16:19
3	2	((electron adj source) with emitter with beam) and (first near2 deflect\$5 near3 stage)	USPAT;	2004/04/29
5	877	(high adj energy adj electron adj diffraction) or (RHEED)	US-PGPUB	16:27
6	1	((high adj energy adj electron adj diffraction) or (RHEED)) and ((electron adj source) with emitter with beam\$2)	USPAT;	2004/04/29
7	4	((high adj energy adj electron adj diffraction) or (RHEED)) and ((electron adj source) with (sample or specimen or target))	US-PGPUB	16:30
8	3	((high adj energy adj electron adj diffraction) or (RHEED)) and ((electron adj source) with (sample or specimen or target))) not 20040065844.pn.	USPAT;	2004/04/29
10	4	(((((high adj energy adj electron adj diffraction) or (RHEED)) and ((electron adj source) with (sample or specimen or target))) not 20040065844.pn.) or ((electron adj source) with emitter with beam) and (RHEED))) and (electron near3 (source or emitter or generator))	US-PGPUB	16:34
11	2	(((((high adj energy adj electron adj diffraction) or (RHEED)) and ((electron adj source) with (sample or specimen or target))) not 20040065844.pn.) or ((electron adj source) with emitter with beam) and (RHEED))) and (electron near3 (source or emitter or generator))) and (first near4 deflect\$5)	USPAT;	2004/04/29
12	1	(((((high adj energy adj electron adj diffraction) or (RHEED)) and ((electron adj source) with (sample or specimen or target))) not 20040065844.pn.) or ((electron adj source) with emitter with beam) and (RHEED))) and (electron near3 (source or emitter or generator))) and (first near4 deflect\$5)) and (second near4 deflect\$5)	US-PGPUB	16:39
9	4	((high adj energy adj electron adj diffraction) or (RHEED)) and ((electron adj source) with (sample or specimen or target))) not 20040065844.pn.) or ((electron adj source) with emitter with beam) and (RHEED))	USPAT;	2004/04/29
4	1	((electron adj source) with emitter with beam) and (RHEED)	US-PGPUB	16:39
13	1	((electron adj source) with emitter with beam) and (first near2 deflect\$5 near3 stage)) not 20040065844.pn.	USPAT;	2004/04/29
14	4	((high adj energy adj electron adj diffraction) or (RHEED)) and ((electron adj source) with (sample or specimen or target))) not 20040065844.pn.) or ((electron adj source) with emitter with beam) and (first near2 deflect\$5 near3 stage)) not 20040065844.pn.)	US-PGPUB	16:38

17	1	(((((high adj energy adj electron adj diffraction) or (RHEED)) and ((electron adj source) with (sample or specimen or target))) not 20040065844.pn.) or (((electron adj source) with emitter with beam) and (first near2 deflect\$5 near3 stage)) not 20040065844.pn.) and (electron near3 (source or emitter or generator))) and (first near4 deflect\$5) and (second near4 deflect\$5)	USPAT; US-PGPUB	2004/04/29 16:58
18	1	(((((high adj energy adj electron adj diffraction) or (RHEED)) and ((electron adj source) with (sample or specimen or target))) not 20040065844.pn.) or (((electron adj source) with emitter with beam) and (first near2 deflect\$5 near3 stage)) not 20040065844.pn.) and (electron near3 (source or emitter or generator))) and (first near4 deflect\$5) and ((second near4 deflect\$5) with (sample or target or specimen))	USPAT; US-PGPUB	2004/04/29 16:49
16	2	(((((high adj energy adj electron adj diffraction) or (RHEED)) and ((electron adj source) with (sample or specimen or target))) not 20040065844.pn.) or (((electron adj source) with emitter with beam) and (first near2 deflect\$5 near3 stage)) not 20040065844.pn.) and (electron near3 (source or emitter or generator))) and (first near4 deflect\$5)	USPAT; US-PGPUB	2004/04/29 16:46
19	0	(((((high adj energy adj electron adj diffraction) or (RHEED)) and ((electron adj source) with (sample or specimen or target))) not 20040065844.pn.) or (((electron adj source) with emitter with beam) and (first near2 deflect\$5 near3 stage)) not 20040065844.pn.) and (electron near3 (source or emitter or generator))) and (first near4 deflect\$5) and ((second near4 deflect\$5) with (sample or target or specimen))) and (magnet\$4 near4 shield\$5)	USPAT; US-PGPUB	2004/04/29 16:47
20	0	(((((high adj energy adj electron adj diffraction) or (RHEED)) and ((electron adj source) with (sample or specimen or target))) not 20040065844.pn.) or (((electron adj source) with emitter with beam) and (first near2 deflect\$5 near3 stage)) not 20040065844.pn.) and (electron near3 (source or emitter or generator))) and (first near4 deflect\$5) and ((second near4 deflect\$5) with (sample or target or specimen))) and (magnet\$4 with shield\$5)	USPAT; US-PGPUB	2004/04/29 16:47
15	4	(((((high adj energy adj electron adj diffraction) or (RHEED)) and ((electron adj source) with (sample or specimen or target))) not 20040065844.pn.) or (((electron adj source) with emitter with beam) and (first near2 deflect\$5 near3 stage)) not 20040065844.pn.) and (electron near3 (source or emitter or generator)))	USPAT; US-PGPUB	2004/04/29 16:47
21	0	(((((high adj energy adj electron adj diffraction) or (RHEED)) and ((electron adj source) with (sample or specimen or target))) not 20040065844.pn.) or (((electron adj source) with emitter with beam) and (first near2 deflect\$5 near3 stage)) not 20040065844.pn.) and (electron near3 (source or emitter or generator))) and (magnet\$4 with shield\$5)	USPAT; US-PGPUB	2004/04/29 16:48

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22	18	((high adj energy adj electron adj diffraction) or (RHEED)) and (magnet\$4 with shield\$5)	USPAT; US-PGPUB	2004/04/29 17:12
23	1	((high adj energy adj electron adj diffraction) or (RHEED)) and (magnet\$4 with shield\$5)) and ((second near4 deflect\$5) with (sample or target or specimen))	USPAT; US-PGPUB	2004/04/29 16:49
25	0	((high adj energy adj electron adj diffraction) or (RHEED)) and (magnet\$4 with shield\$5)) and (aperture with (point\$3 or slit))) and (casing with aperture with (point or slit))	USPAT; US-PGPUB	2004/04/29 17:11
24	2	((high adj energy adj electron adj diffraction) or (RHEED)) and (magnet\$4 with shield\$5)) and (aperture with (point\$3 or slit))	USPAT; US-PGPUB	2004/04/29 16:54
26	1	((high adj energy adj electron adj diffraction) or (RHEED)) and (magnet\$4 with shield\$5)) and ((second near4 deflect\$5) with beam with correct\$5)	USPAT; US-PGPUB	2004/04/29 16:56
27	17	((high adj energy adj electron adj diffraction) or (RHEED)) and (magnet\$4 with shield\$5)) not 20040065844.pn.	USPAT; US-PGPUB	2004/04/29 16:56
28	0	((high adj energy adj electron adj diffraction) or (RHEED)) and (magnet\$4 with shield\$5)) not 20040065844.pn.) and (aperture with foil)	USPAT; US-PGPUB	2004/04/29 16:57
29	0	((high adj energy adj electron adj diffraction) or (RHEED)) not 20040065844.pn.) and (aperture with foil)	USPAT; US-PGPUB	2004/04/29 16:58
30	876	((high adj energy adj electron adj diffraction) or (RHEED)) not 20040065844.pn.	USPAT; US-PGPUB	2004/04/29 16:58
31	4	((high adj energy adj electron adj diffraction) or (RHEED)) not 20040065844.pn.) and (second near4 deflect\$5)	USPAT; US-PGPUB	2004/04/29 17:13
32	1	((high adj energy adj electron adj diffraction) or (RHEED)) and (magnet\$4 with shield\$5)) and (casing with aperture)	USPAT; US-PGPUB	2004/04/29 17:11
33	17	((high adj energy adj electron adj diffraction) or (RHEED)) and (magnet\$4 with shield\$5)) not 20040065844.pn.) and (magnet\$4 with shield\$5)	USPAT; US-PGPUB	2004/04/29 17:12
34	0	((high adj energy adj electron adj diffraction) or (RHEED)) and (magnet\$4 with shield\$5)) not 20040065844.pn.) and (magnet\$4 with shield\$5)) and (second near4 deflect\$5)	USPAT; US-PGPUB	2004/04/29 17:13